

On the use of microwave holography to detect surface defects of rails and measure the rail profile

Zhuravlev A, Razevig V, Ivashov S, Skrebkov A, Alekseev V.

Sensors (Basel)

2019; 19(6):s19061376

ARTICLE IDENTIFIERS

DOI: 10.3390/s19061376

PMID: 30893933

PMCID: not available

JOURNAL IDENTIFIERS

LCCN: 2002242115

pISSN: not available

eISSN: 1424-8220

OCLC ID: 47250782

CONS ID: not available

US National Library of Medicine ID: 101204366

This article was identified from a query of the SafetyLit database.